

1) UL Unjointed Finger Probe



Application:

- 1) According to: IEC62368-1:2010 V.1.3
- 2) Mainly used for the inspection to prevent the body touch dangerous live parts, heating or hot parts, mechanical components, as well as inspection of solid foreign bodies into the equipment. It is necessary for protection against electric shock test of household and similar electrical appliances.

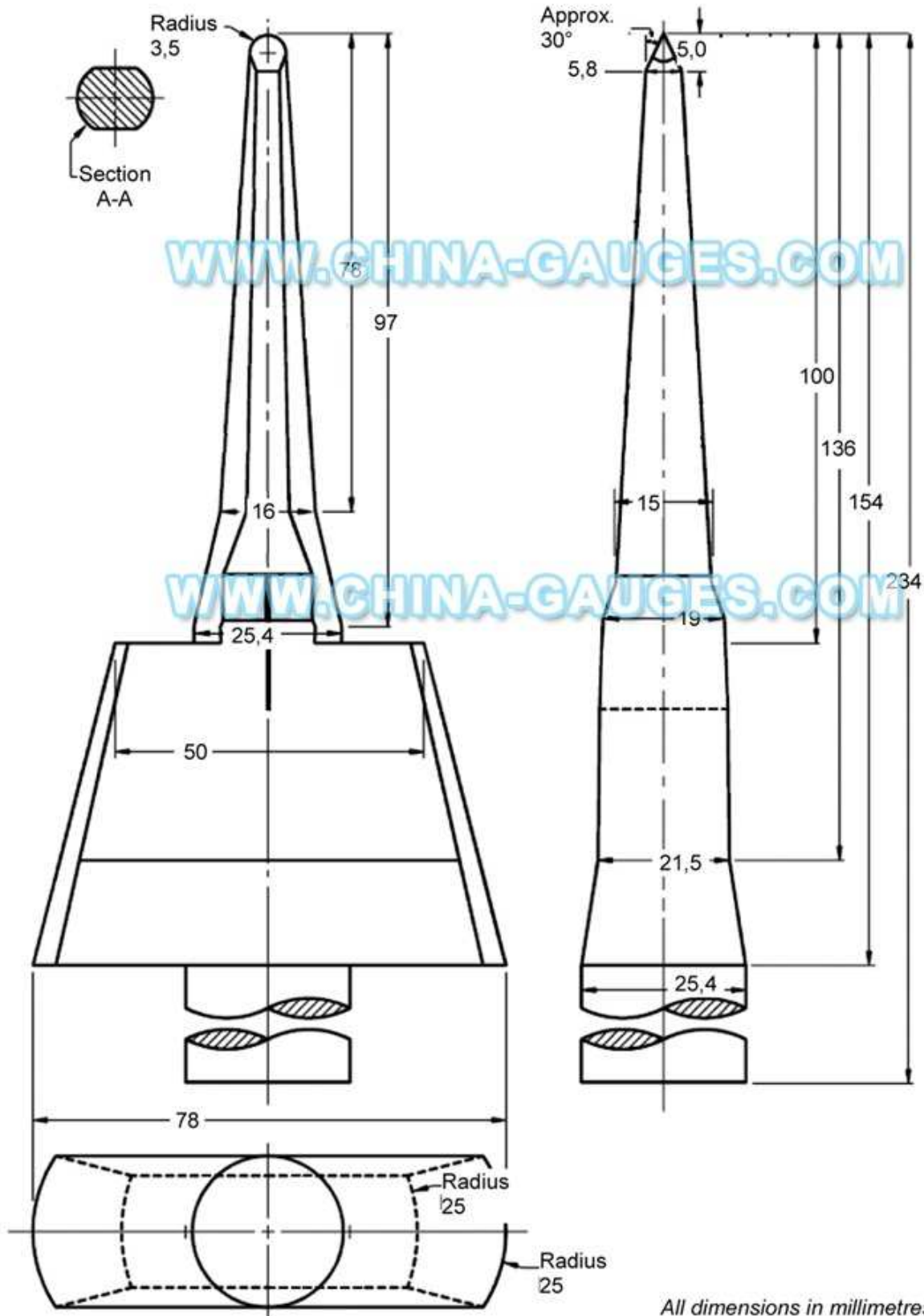
Technical:

Test probe base diameter: 25.4 mm (1 inch)

Test probe fingertip radius: 3.5 mm / 30°

Test probe length: 101.6 mm (4 inch)

Material: Stainless steel, nylon.



2) Test Probe B



The Jointed Test Finger is a precision test probe made according to Figure 2 (Fig. 2) of the IEC 61032 (Test probe B) and is used to simulate a human finger. It is also used by the standards of IEC 62368 and in most of the rules involved in the verification of accessibility to live parts.

Technical Parameters:

1. Knurled Finger Diameter:12 mm
2. Knurled Finger Length:80 mm
3. Baffle Plate Diameter:50 mm
4. Baffle Plate Length:100 mm
5. Baffle thickness:20 mm

Application:

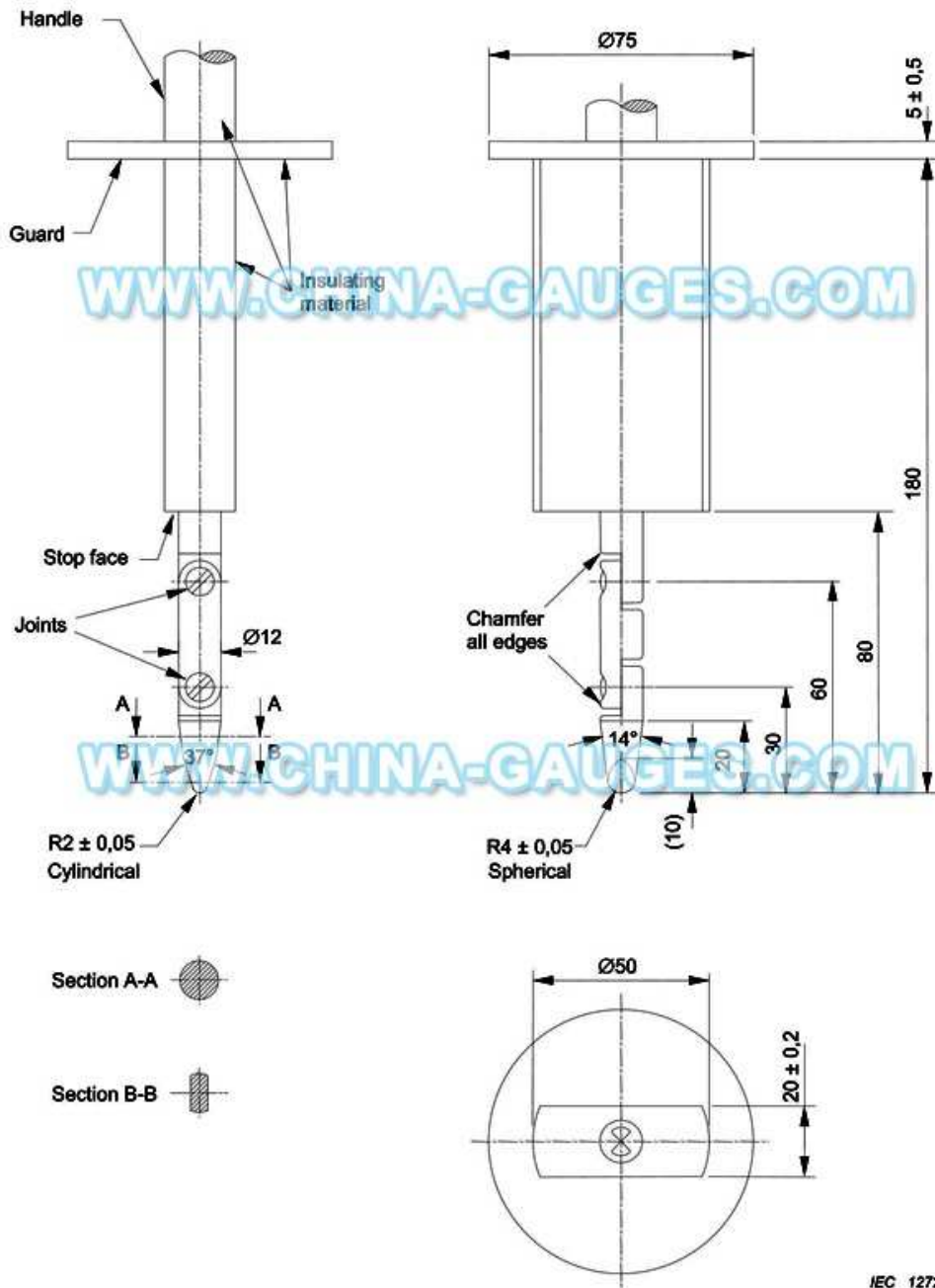
1. The joint part of The Standard Test Knurled Finger Probe can't touch the live parts or close to the dangerous parts, and 50 mm to 20 mm baffle plate cannot enter.
2. In the prevent electric shock test, wirings, power devices, and lighting devices are needed.

Notes:

Both joints shall permit movement in the same plane and the same direction through an angle of 90° with a 0° to +10° tolerance.

62368-1 © IEC:2010(E)

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Tolerances on dimensions without specific tolerances:

- 14° and 37° angles: ±15'
- on radii: ±0,1 mm
- on linear dimensions:

≤15 mm:	0 $-0,1$ mm
>15 mm ≤ 25 mm:	±0,1 mm
>25 mm:	±0,3 mm

NOTE This jointed test probe is taken from Figure 2, test probe B of IEC 61032:1997.

Figure V.2 – Jointed test probe for equipment not likely to be accessible to children

3) Blunt Probe

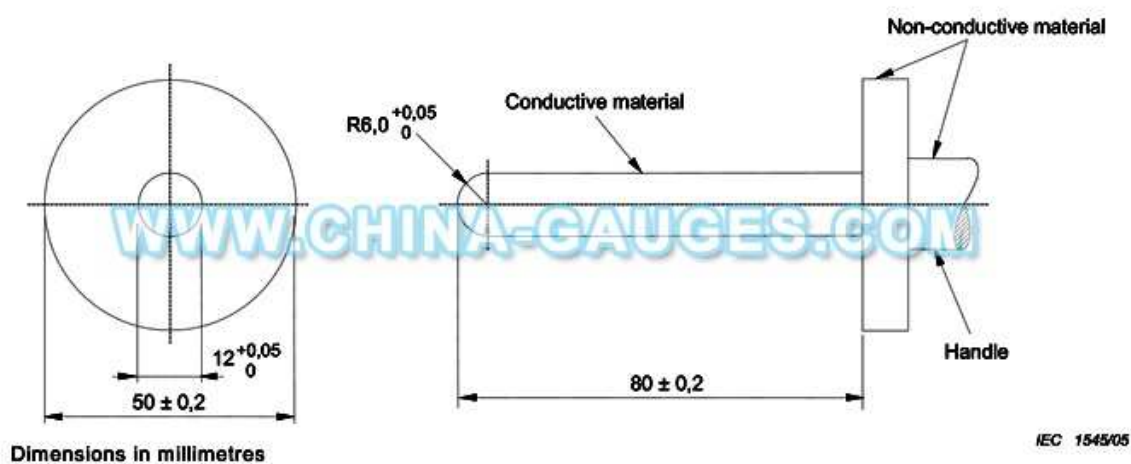


Purpose:

Blunt Probe meets IEC60950 Figure 2C and IEC62368 Figure V.3 standards. is for the absolute share TNV circuits information technology to see if they provide sufficient protection.

Technical Parameter:

- Test probe diameter: 12 mm
- Test probe length: 80 mm
- Baffle plate thickness: 5 mm
- Baffle plate diameter: 50 mm



NOTE This test probe is taken from Figure 2c, IEC 60950-1:2005.

Figure V.3 – Blunt probe

4) Wedge Probe

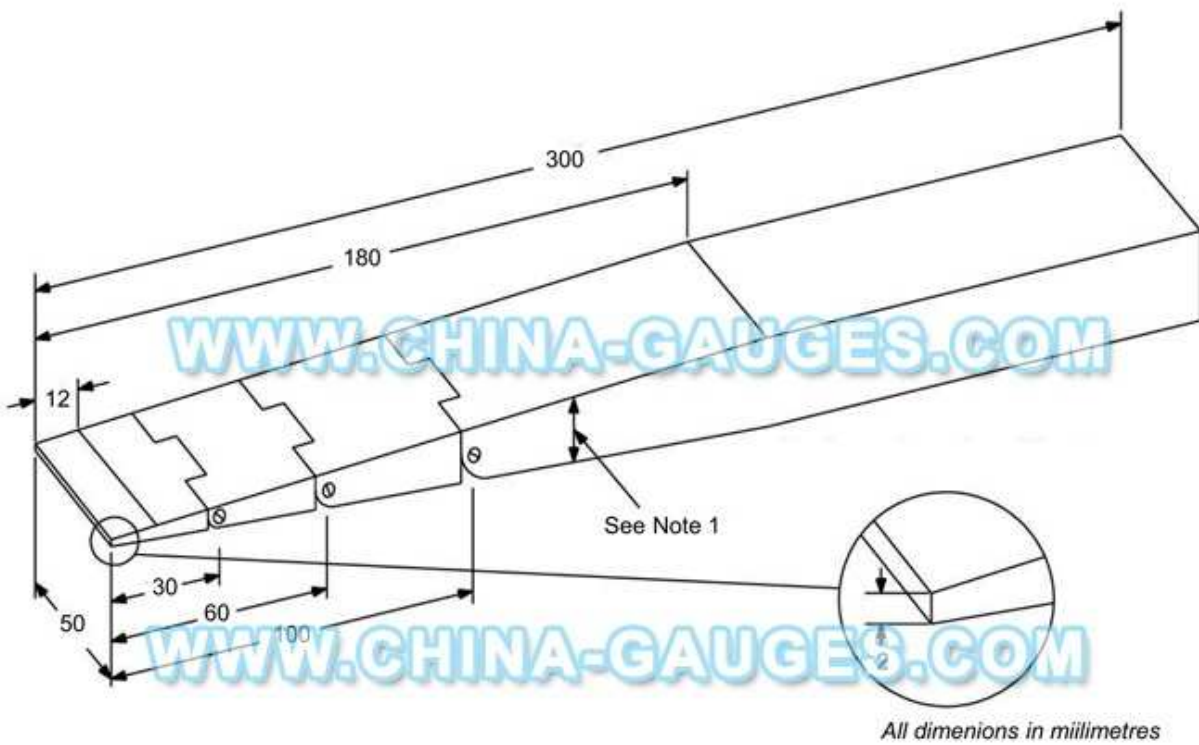


1. Reference standard:

IEC 62368-1 Figure V.4

2. Product Details:

This product is used for testing access to document shredders. The Jointed Accessibility Wedge Probe is a high precision probe made in exact accordance with UL and IEC standards such as IEC 62368-1 Figure V.4.



All dimensions in millimetres

Tolerances on linear dimensions without specific tolerances:

≤25 mm: ±0,13 mm

>25 mm: ±0,3 mm

The thickness of the probe varies linearly, with slope changes at the following points along the probe:

Distance from probe tip mm	Probe thickness mm
0	2
12	4
180	24

Figure V.4 – Wedge probe

5) Diameter 1 mm, Length 20 mm Terminal Probe



Application:

According to: IEC62368-1 V.1.6 \ IEC60065:2005 9.1.4

Technical:

Test probe diameter: 1,0 mm

Test probe length: 20 mm

Force: 1 Newton

Material: Stainless steel, nylon.

